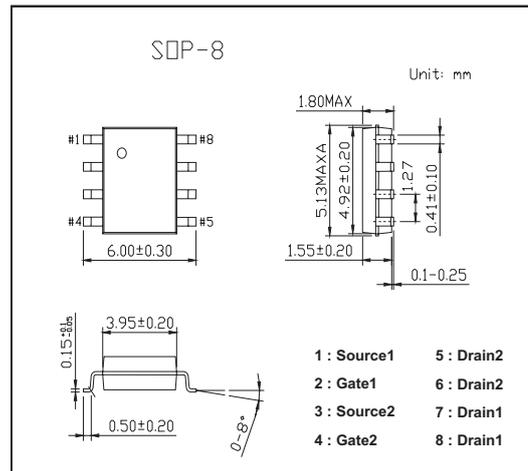
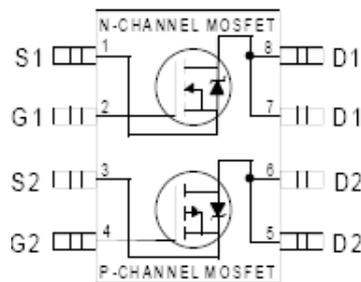


# HEXFET<sup>®</sup> Power MOSFET

## KRF9952

### ■ Features

- Generation V Technology
- Ultra Low On-Resistance
- Dual N and P Channel MOSFET
- Surface Mount
- Very Low Gate Charge and Switching Losses
- Fully Avalanche Rated



### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	N-Channel	P-Channel	Unit
Drain-Source Voltage	$V_{DS}$	30		V
Gate-to-Source Voltage	$V_{GS}$	$\pm 20$		V
Continuous Drain Current, $V_{GS} @ 10V @ T_a = 25^\circ\text{C}$	$I_D$	3.5	-2.3	A
Continuous Drain Current, $V_{GS} @ 10V @ T_a = 70^\circ\text{C}$	$I_D$	2.8	-1.8	
Pulsed Drain Current *1	$I_{DM}$	16	-10	
Continuous Source Current (Diode Conduction)	$I_S$	1.7	-1.3	A
Power Dissipation @ $T_a = 25^\circ\text{C}$	$P_D$	2		W
Power Dissipation @ $T_a = 70^\circ\text{C}$		1.3		
Single Pulse Avalanche Energy	$E_{AS}$	44	57	mJ
Avalanche Current	$I_{AR}$	2.0	-1.3	A
Repetitive Avalanche Energy	$E_{AR}$	0.25		mJ
Peak Diode Recovery $dv/dt$ *2	$dv/dt$	5.0	-5	V/ns
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to + 150		$^\circ\text{C}$
Maximum Junction-to-Ambient *3	$R_{\theta JA}$	62.5		$^\circ\text{C/W}$

\*1 Repetitive rating; pulse width limited by max. junction temperature.

\*2 N-Channel  $I_{SD} \leq 2.0A$ ,  $di/dt \leq 100A/\mu s$ ,  $V_{BD} \leq V_{(BR)DSS}$ ,  $T_J \leq 150^\circ\text{C}$

P-Channel  $I_{SD} \leq -1.3A$ ,  $di/dt \leq 84A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 150^\circ\text{C}$

\*3 Surface mounted on FR-4 board,  $t \leq 10\text{sec}$ .

## KRF9952

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250 μA	N-Ch	30			V
		V <sub>GS</sub> = 0V, I <sub>D</sub> = -250 μA	P-Ch	-30			
Breakdown Voltage Temp. Coefficient	ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	I <sub>D</sub> = 1mA, Reference to 25°C	N-Ch		0.015		V/°C
		I <sub>D</sub> = -1mA, Reference to 25°C	P-Ch		0.015		
Static Drain-to-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 2.2A*1	N-Ch		0.08	0.10	Ω
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 1.0A*1			0.12	0.15	
Static Drain-to-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -1.0A*1	P-Ch		0.165	0.250	Ω
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -0.5A*1			0.290	0.400	
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	N-Ch	1.0			V
		V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	P-Ch	-1.0			
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 15V, I <sub>D</sub> = 3.5A*1	N-Ch		12		S
		V <sub>DS</sub> = -15V, I <sub>D</sub> = -2.3A*1	P-Ch		2.4		
Drain-to-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V	N-Ch			2.0	μA
		V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V	P-Ch			-2.0	
		V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C	N-Ch			25	
		V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C	P-Ch			-25	
Gate-to-Source Forward Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ±20V	N-Ch			±100	nA
			P-Ch				
Total Gate Charge	Q <sub>g</sub>	N-Channel I <sub>D</sub> = 1.8A, V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	N-Ch		6.9	14	nC
Gate-to-Source Charge	Q <sub>gs</sub>	P-Channel	N-Ch		1.0	2.0	
			P-Ch		1.7	3.4	
Gate-to-Drain ("Miller") Charge	Q <sub>gd</sub>	I <sub>D</sub> = -2.3A, V <sub>DS</sub> = -10V, V <sub>GS</sub> = -10V	N-Ch		1.8	3.5	
			P-Ch		1.1	2.2	
Turn-On Delay Time	t <sub>d(on)</sub>	N-Channel V <sub>DD</sub> = 10V, I <sub>D</sub> = 1.0A, R <sub>G</sub> = 6.0 Ω	N-Ch		6.2	12	ns
Rise Time	t <sub>r</sub>	R <sub>D</sub> = 10 Ω P-Channel	N-Ch		8.8	18	
			P-Ch		14	28	
Turn-Off Delay Time	t <sub>d(off)</sub>	V <sub>DD</sub> = -10V, I <sub>D</sub> = -1.0A, R <sub>G</sub> = 6.0 Ω R <sub>D</sub> = 10 Ω	N-Ch		13	26	
			P-Ch		20	40	
Fall Time	t <sub>f</sub>		N-Ch		3.0	6.0	
			P-Ch		6.9	14	
Input Capacitance	C <sub>iss</sub>	N-Channel V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1.0MHz	N-Ch		190		pF
			P-Ch		190		
Output Capacitance	C <sub>oss</sub>	P-Channel	N-Ch		120		
			P-Ch		110		
Reverse Transfer Capacitance	C <sub>rss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = -15V, f = 1.0MHz	N-Ch		61		
			P-Ch		54		
Continuous Source Current (Body Diode)	I <sub>S</sub>		N-Ch			1.7	A
			P-Ch				
Pulsed Source Current (Body Diode) *2	I <sub>SM</sub>		N-Ch			16	A
			P-Ch				

## KRF9952

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25°C, I <sub>S</sub> = 1.25A, V <sub>GS</sub> = 0V*3		0.82	1.2	V
		T <sub>J</sub> = 25°C, I <sub>S</sub> = -1.25A, V <sub>GS</sub> = 0V*3		-0.82	-1.2	
Reverse Recovery Time	t <sub>rr</sub>	N-Channel		27	53	ns
		T <sub>J</sub> = 25°C, I <sub>F</sub> = 1.25A, di/dt = 100A/μs*1	P-Channel		27	
Reverse RecoveryCharge	Q <sub>rr</sub>	P-Channel		28	57	nC
		T <sub>J</sub> = 25°C, I <sub>F</sub> = -1.25A, di/dt = -100A/μs*1	P-Channel		31	

\*1 Pulse width ≤ 300 μs; duty cycle ≤ 2%.

\*2 Repetitive rating; pulse width limited by max. junction temperature.

\*3 N-Channel Starting T<sub>J</sub> = 25°C, L = 22mH R<sub>G</sub> = 25 Ω, I<sub>AS</sub> = 2.0A.

P-Channel Starting T<sub>J</sub> = 25°C, L = 67mH R<sub>G</sub> = 25 Ω, I<sub>AS</sub> = -1.3A.